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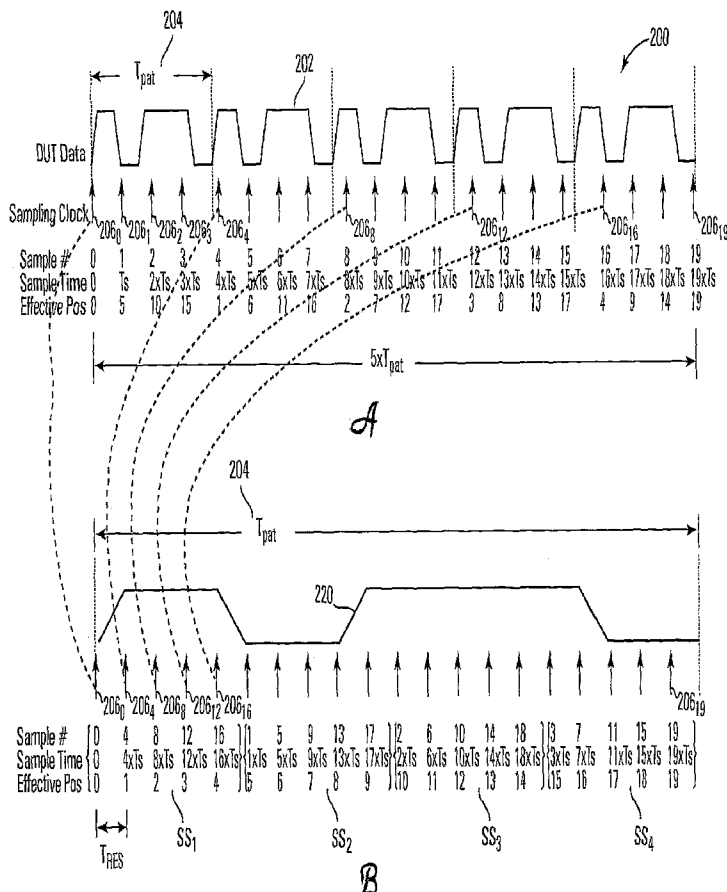
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(57) **Abstract:** A method of jitter measurement is provided and includes sampling a device-under-test (DUT) output signal, having a repeating pattern, using an asynchronous clock over a desired period of time and mapping the samples onto a single period of the repeating pattern. Each period of the repeating pattern is sampled at least twice. A sampling frequency of the asynchronous clock is based on user inputs. Sampling the DUT signal comprises capturing logical state information representing each edge of a single period of the DUT signal at least once. The method further includes, separating the samples into subsets and mapping the sample subsets onto a single period of the repeating pattern, processing the samples within each subset independently of samples in other subsets, and combining results of the processed subsets and processing the combined results of the subsets.



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